

**Notice of References Cited**

Application/Control No.

10/599,523

Applicant(s)/Patent Under  
Reexamination  
YOUN ET AL.

Examiner

FRANK D. DUCHENEAUX

Art Unit

1794

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0161989	08-2003	Funakoshi, Satoru	428/71
*	B	US-6,749,934	06-2004	Nagayama et al.	428/364
*	C	US-5,294,394	03-1994	Sakai et al.	264/135
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 945253 A2	09-1999		BASSETT et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.